

Figure 1a (prior art)

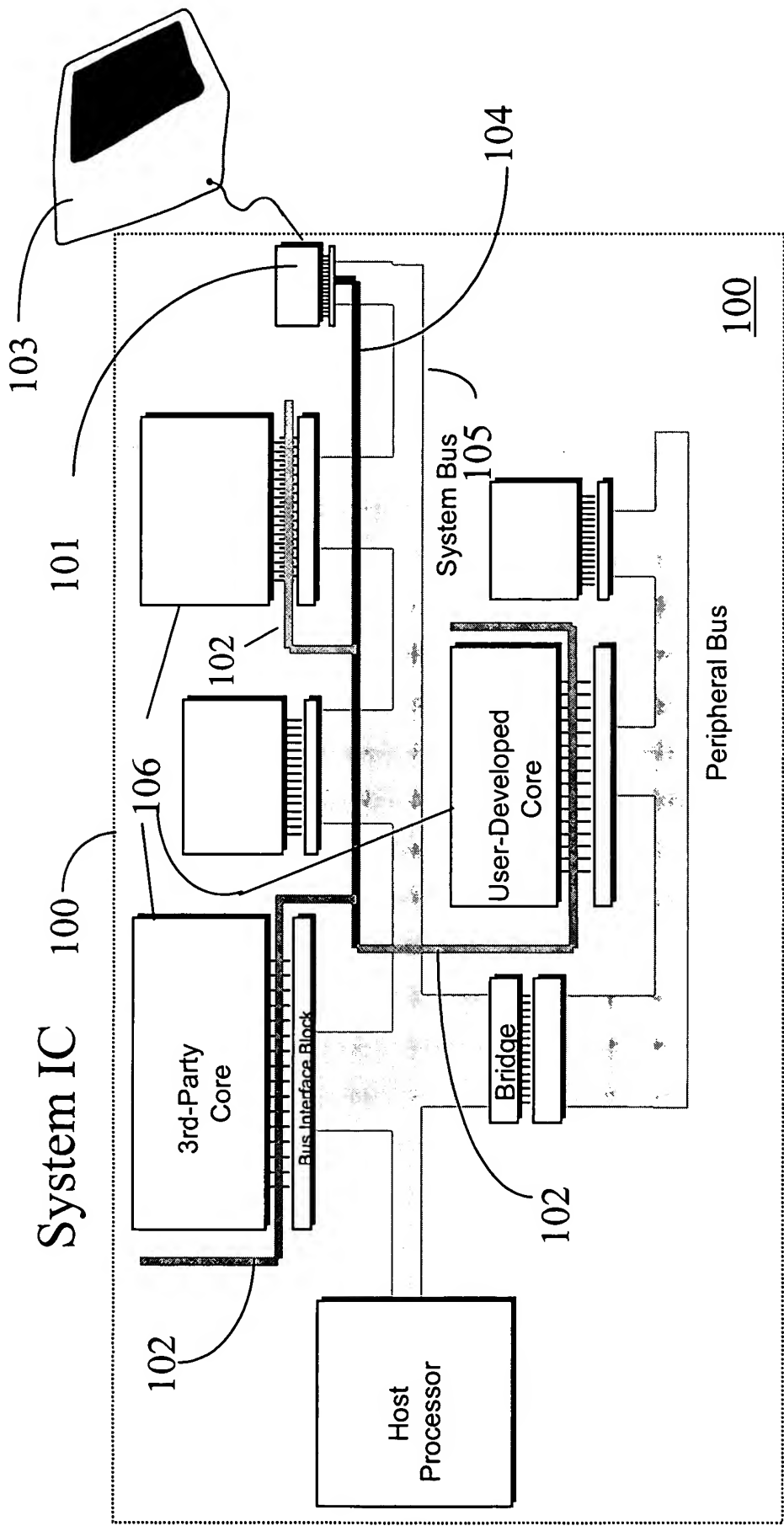


Figure 1b

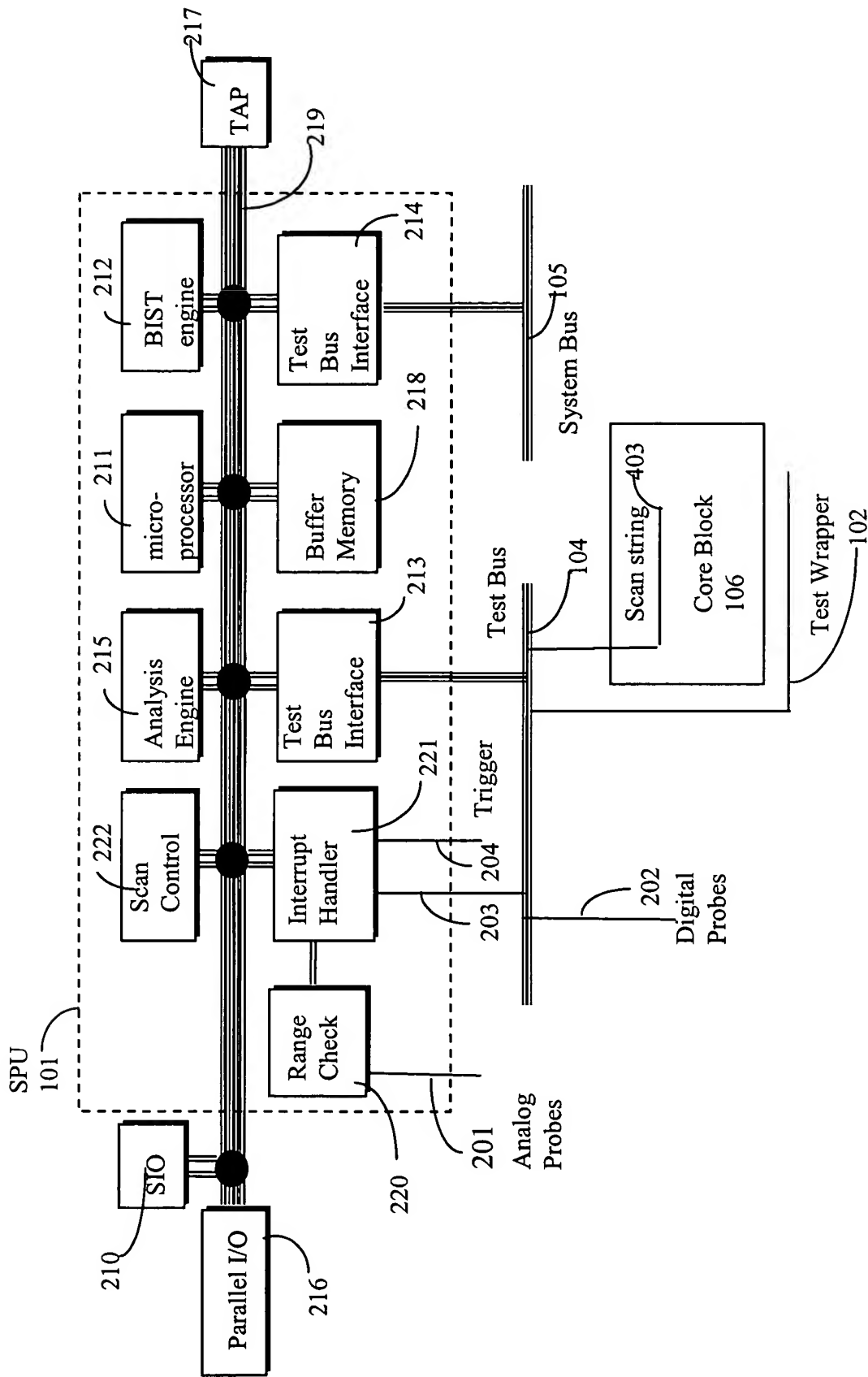


Figure 2

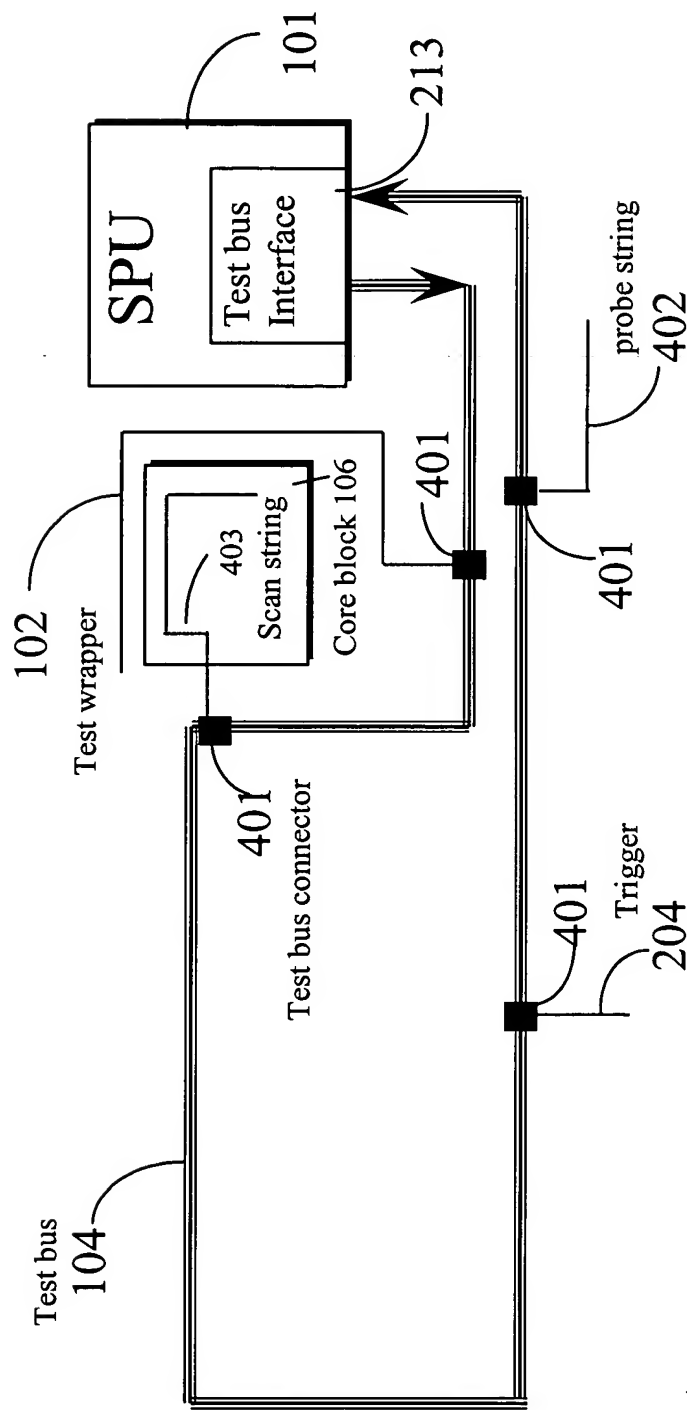


Figure 3a

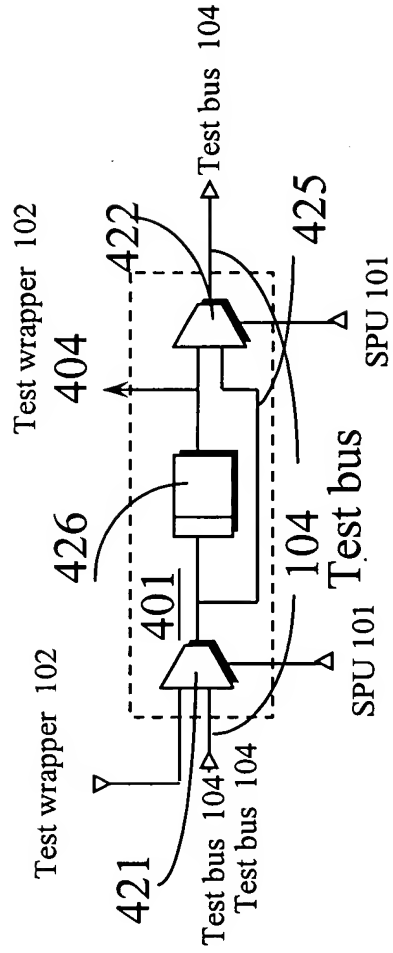


Figure 3b

Preferred Embodiment of Test Bus Connector

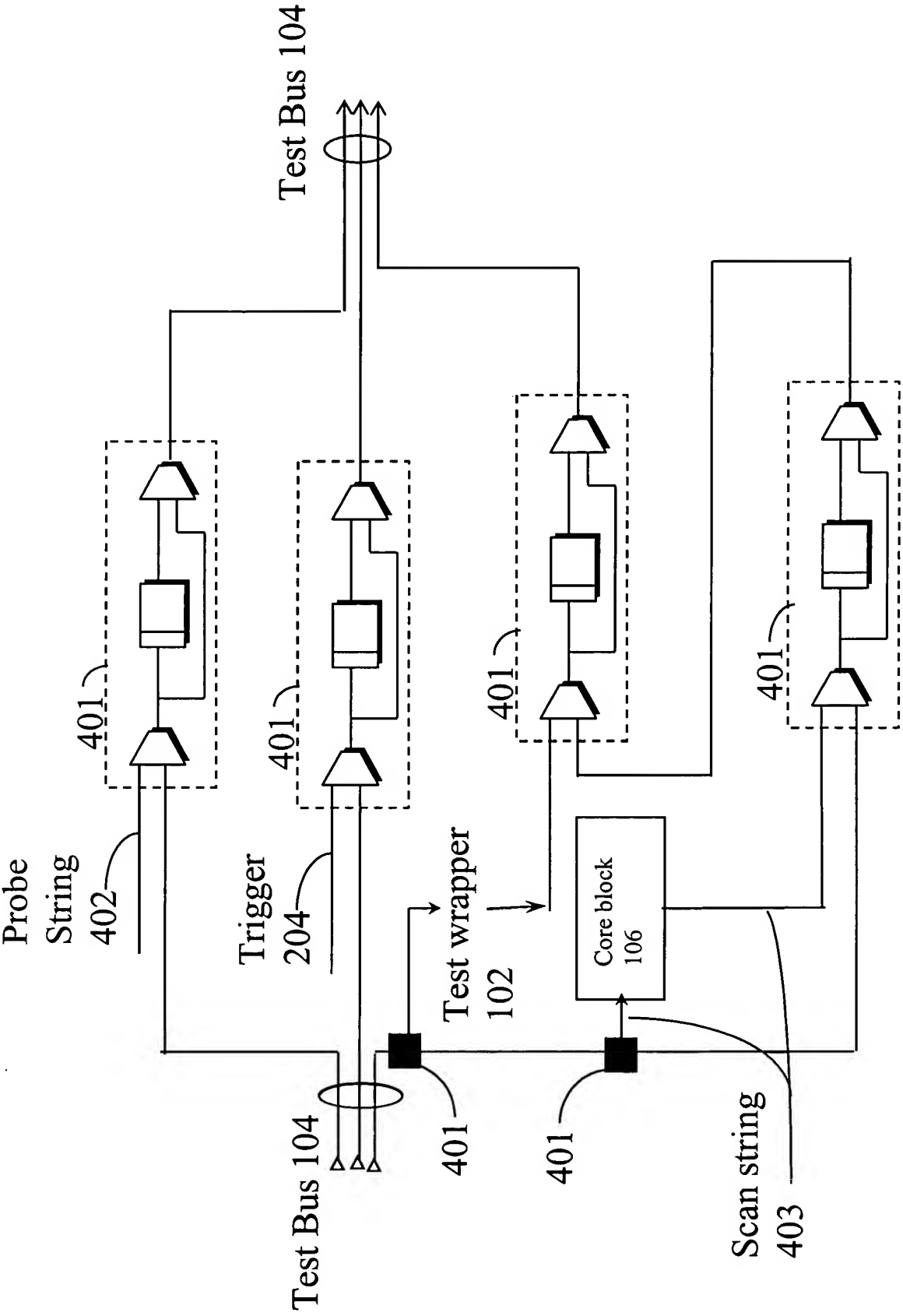


Figure 3c
Connecting Probe String, Test Wrapper or Scan String to Test Bus

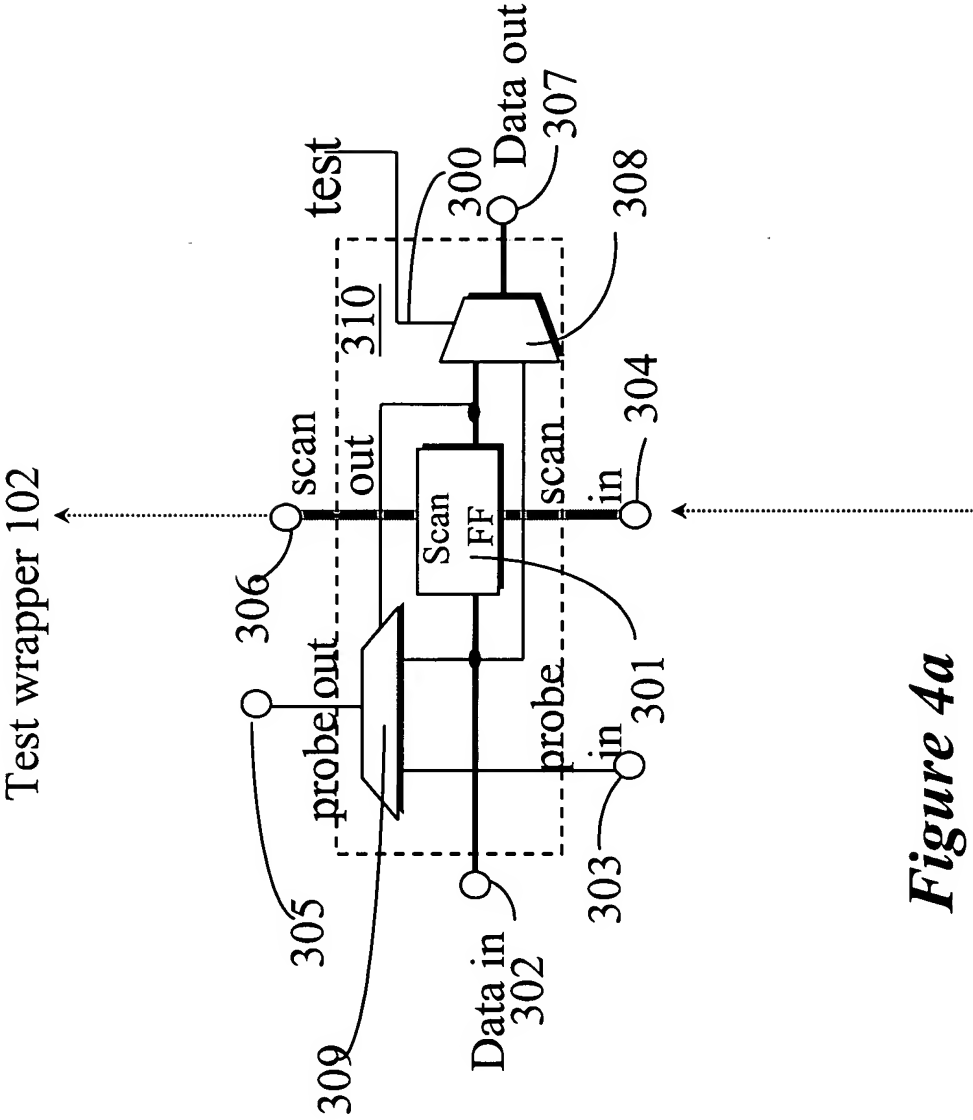


Figure 4a

Preferred Embodiment of Block Input/Output Port Connector

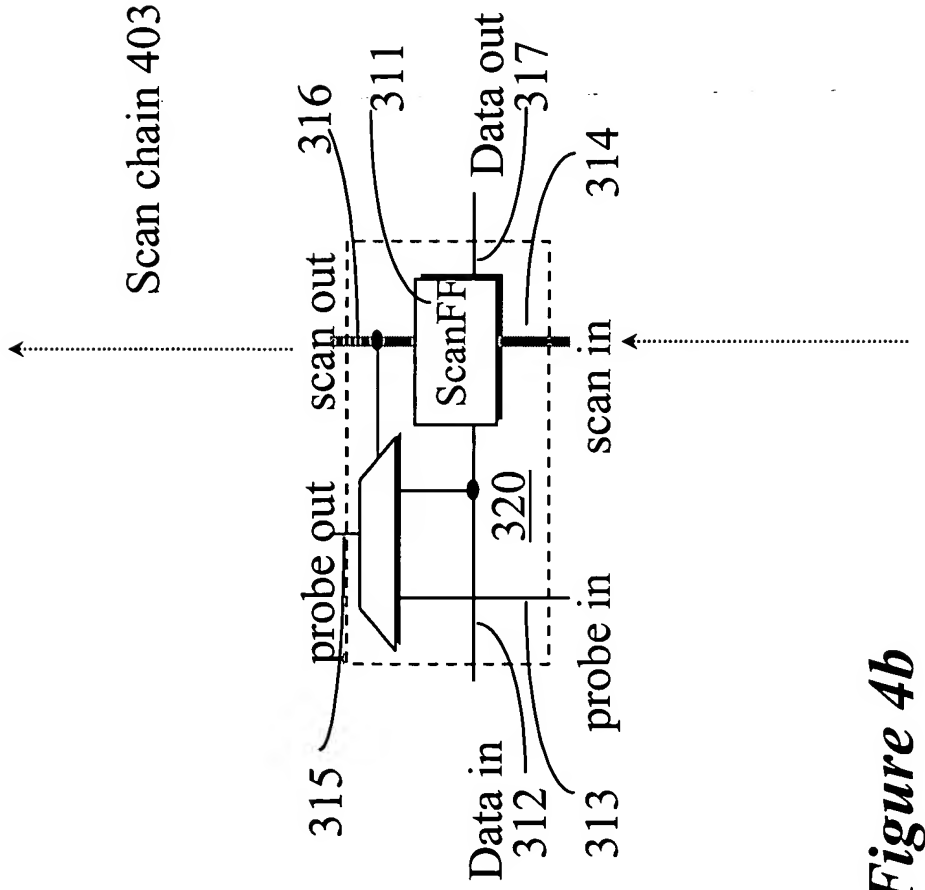


Figure 4b

Preferred Embodiment of Block Scan Connector

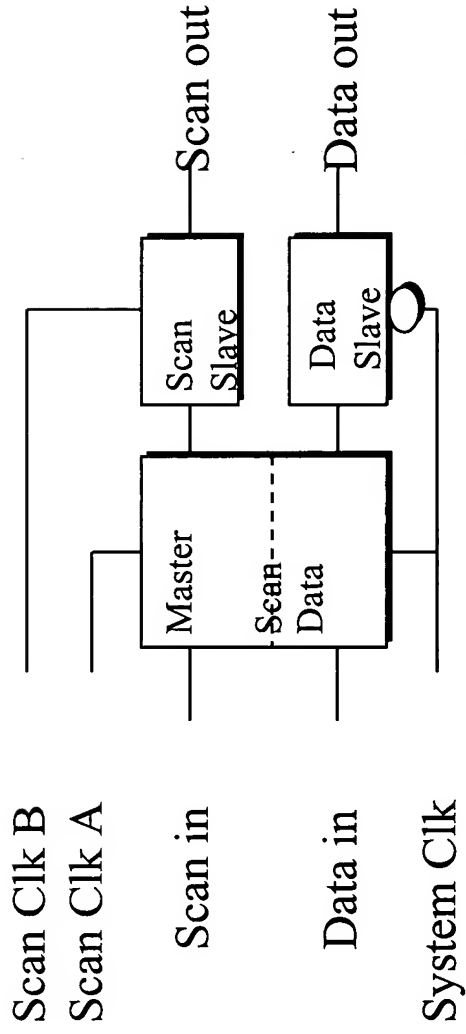


Figure 5

Internal Scan Element with Separate Scan-Slave and Data-Slave:
(prior art)

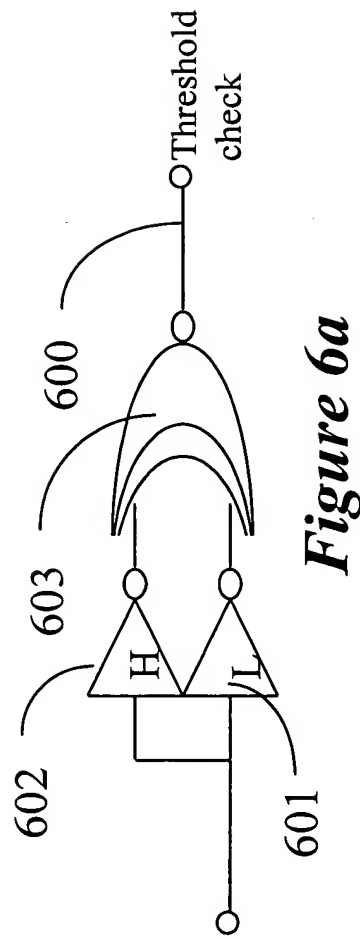


Figure 6a

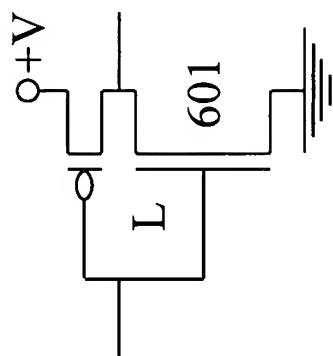


Figure 6b

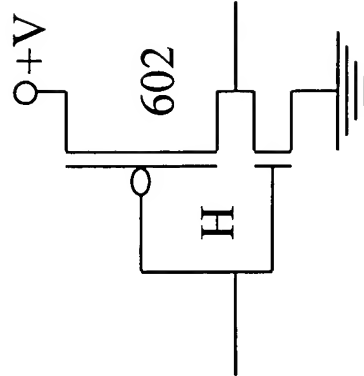


Figure 6c

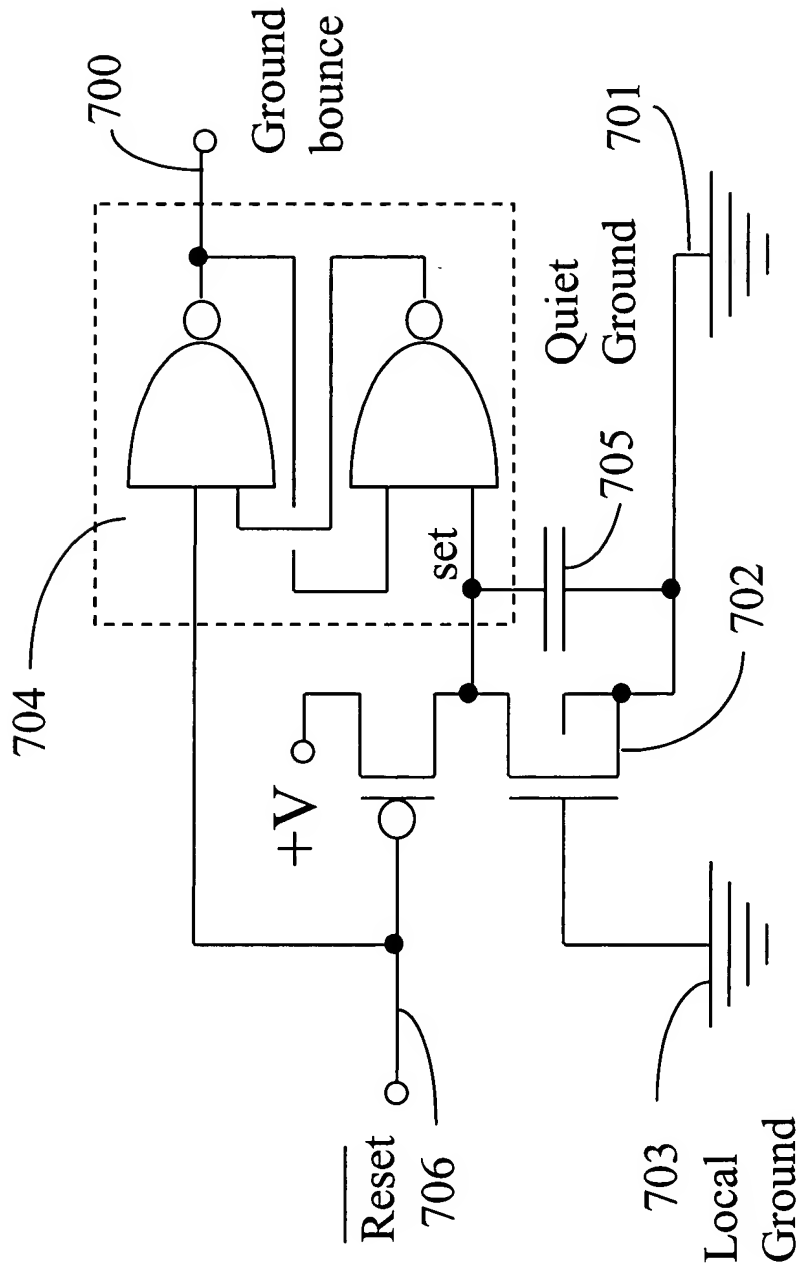


Figure 7

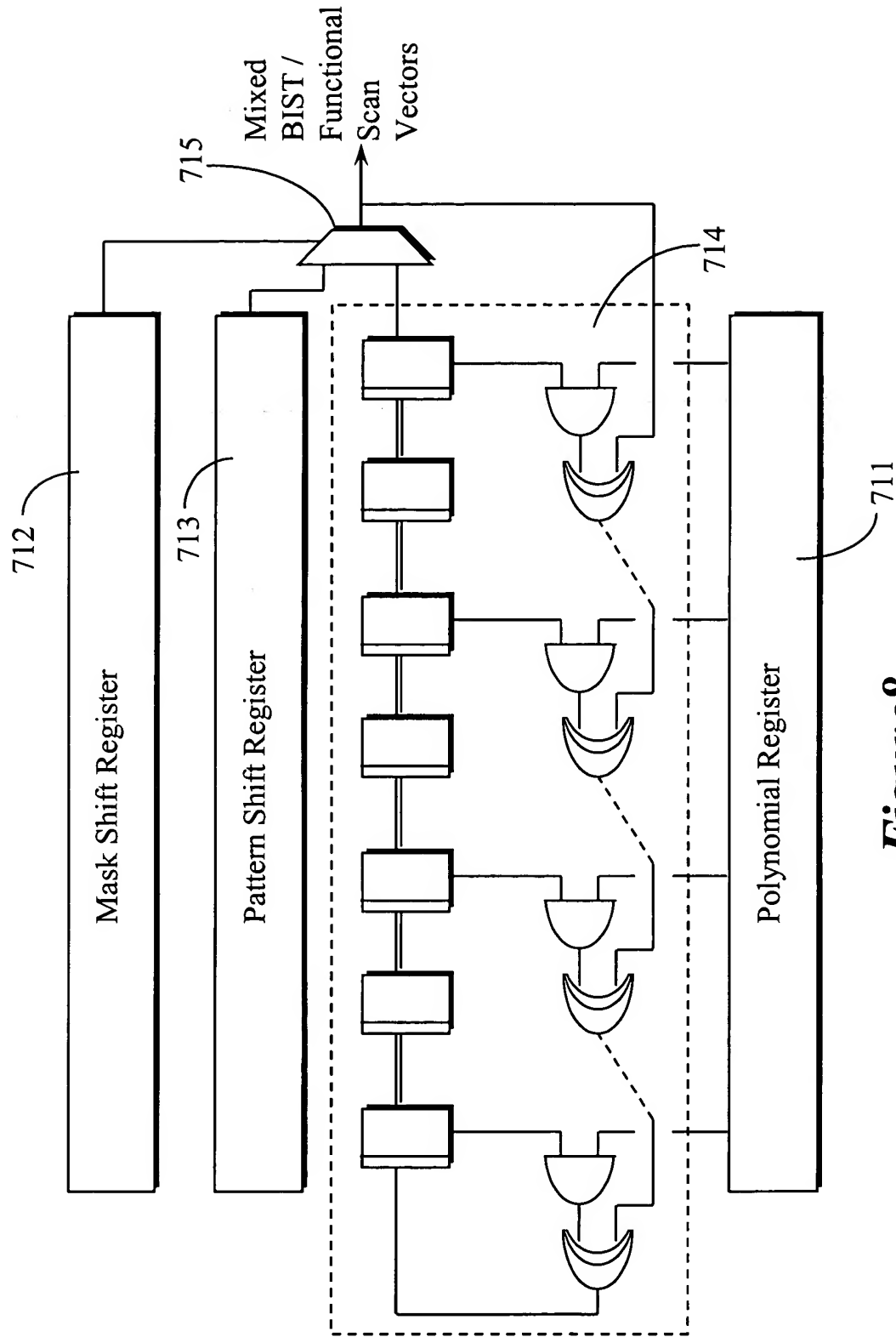


Figure 8

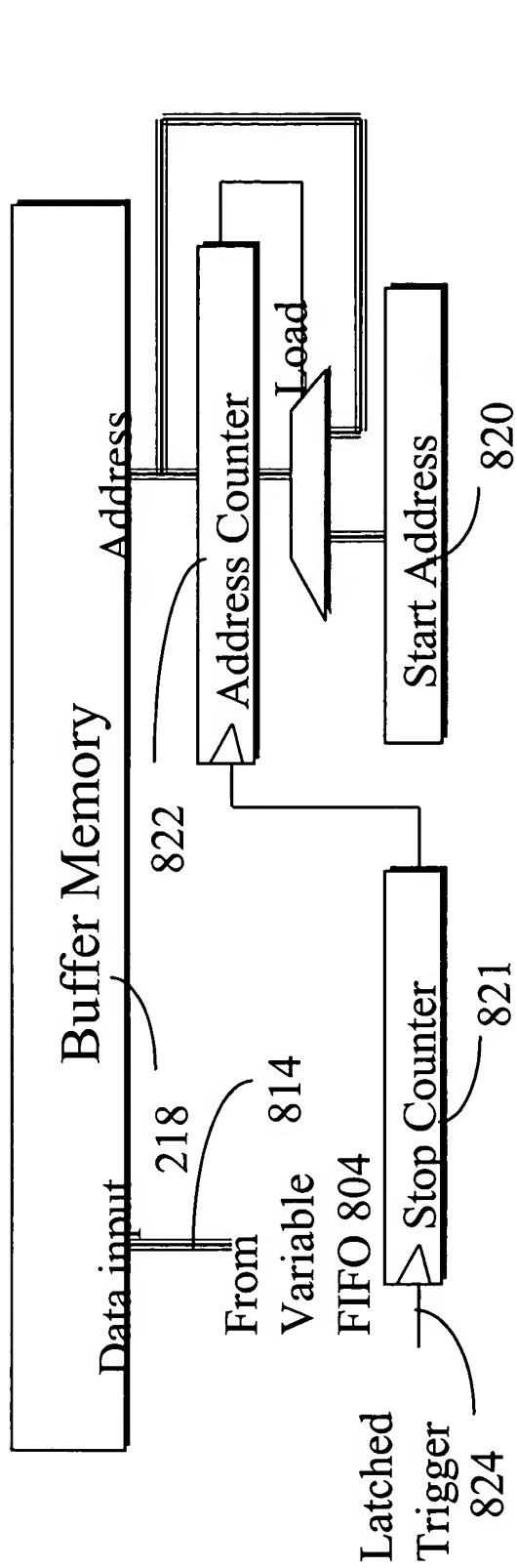


Figure 9c

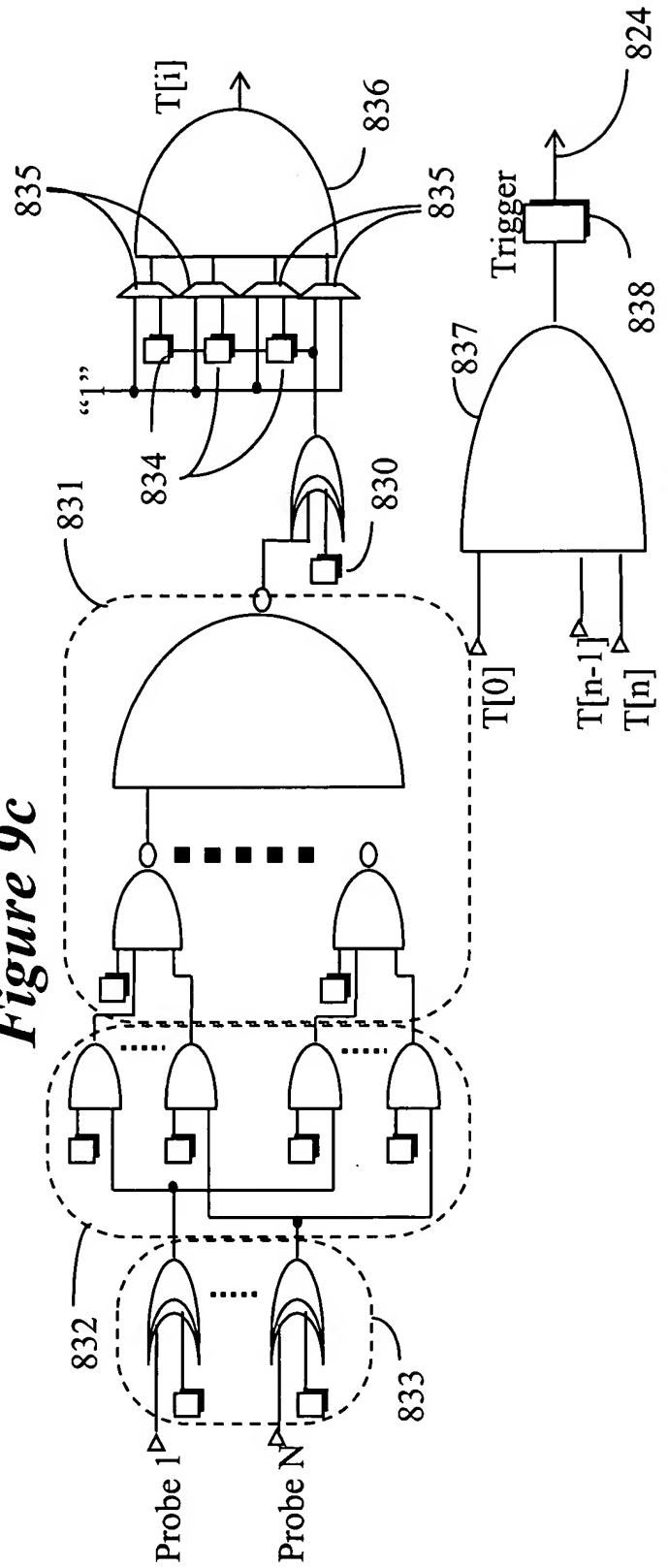


Figure 9d

Figure 11

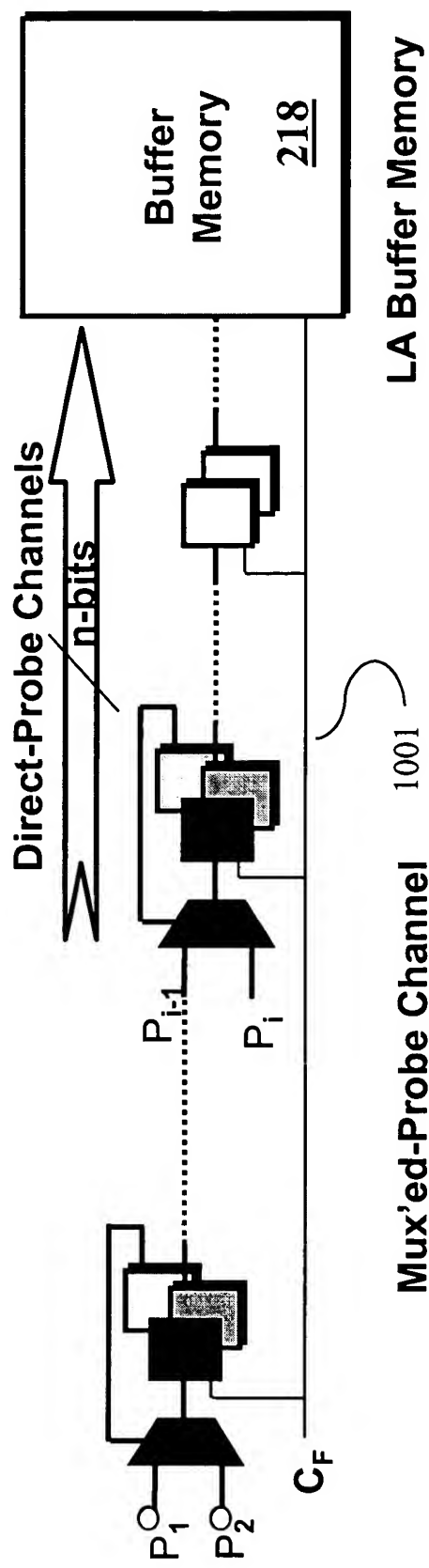


Figure 12

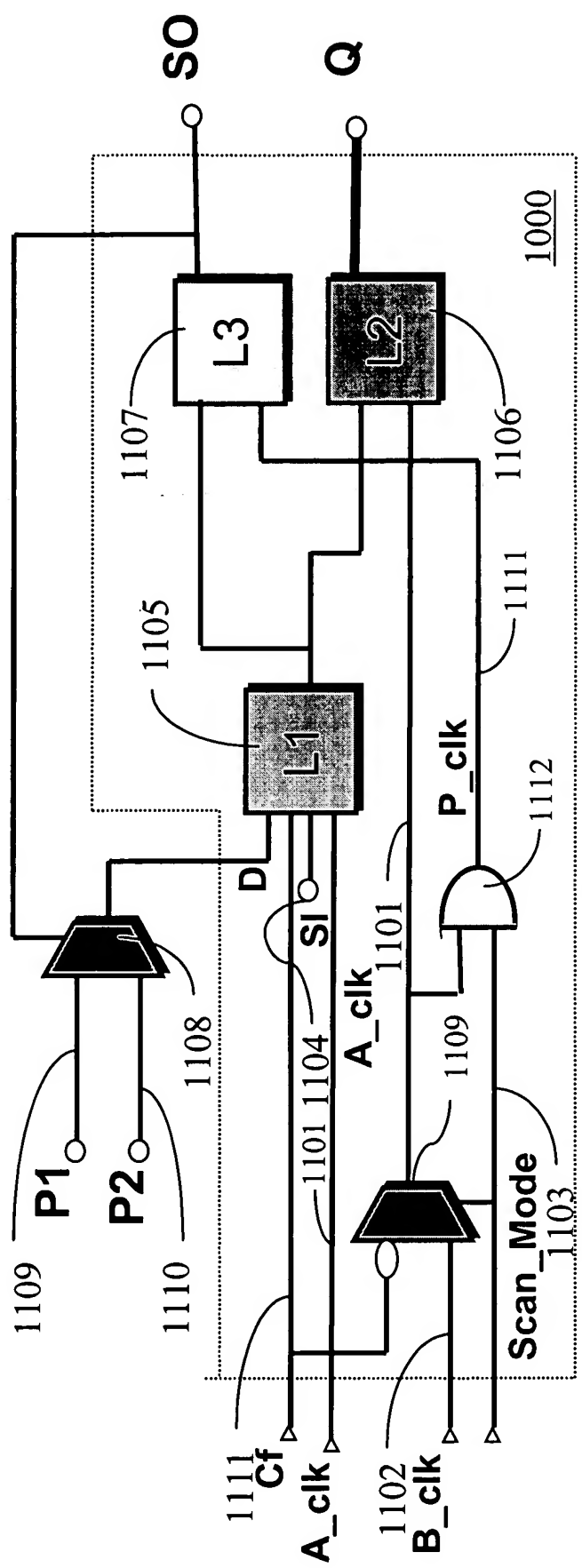


Figure 13